

FAIR, a front-end ASIC for infrared detector readout

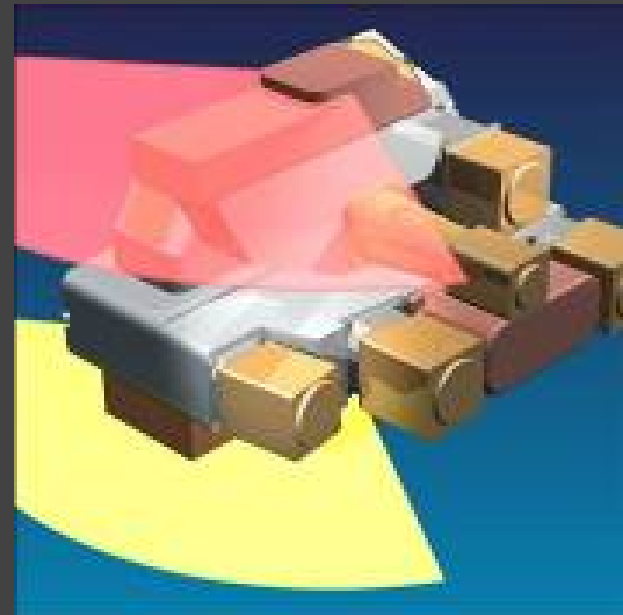
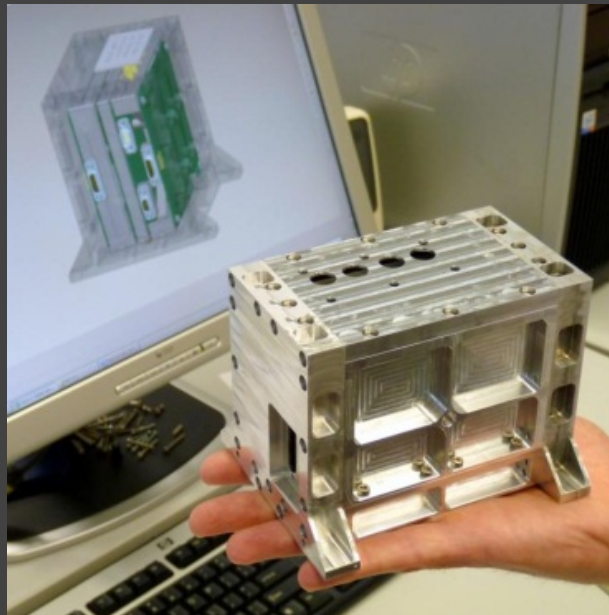
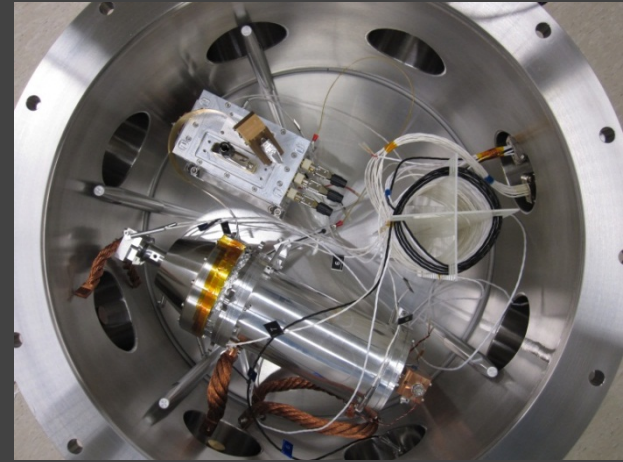
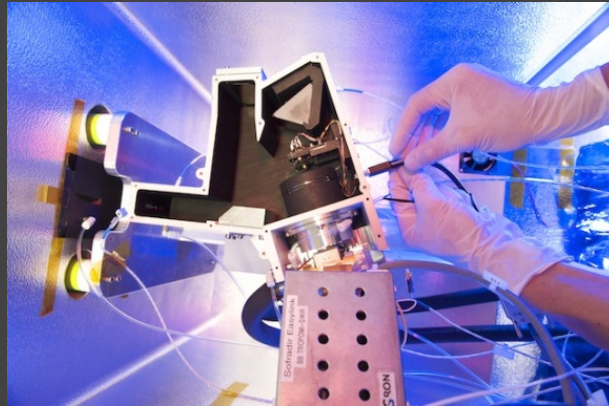


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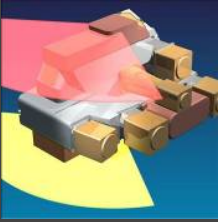
dr. ir. Jan-Rutger Schrader – FAIR project manager

dr. Avri Selig – head of Earth and Planetary Science division

Our heritage: Tropospheric Monitoring (Tropomi) UVN-SWIR instrument



SRON heritage from Tropomi: Essential parts to be integrated in ASIC



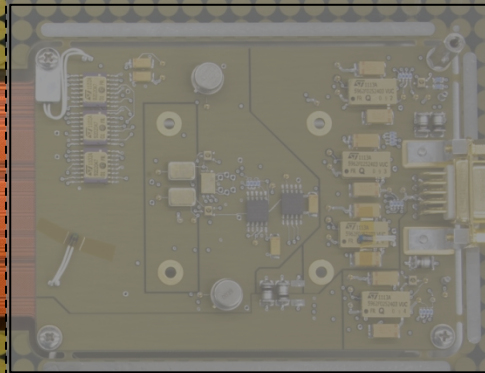
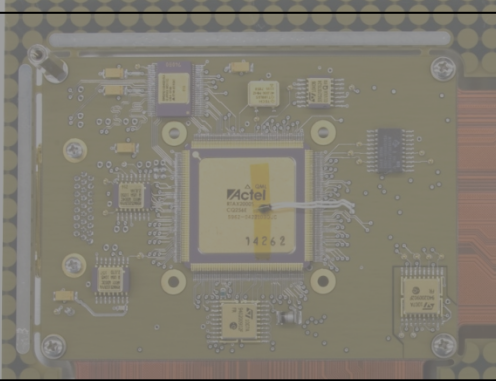
**NOT
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**YES
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Vendor-specific

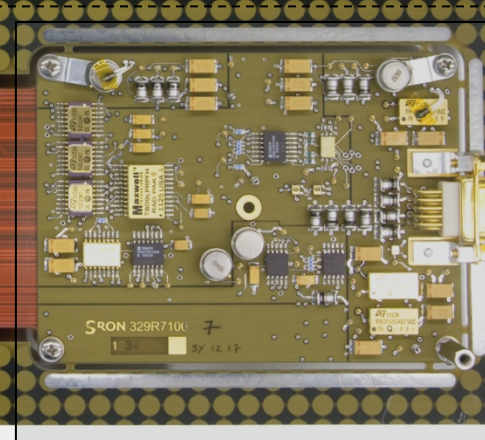
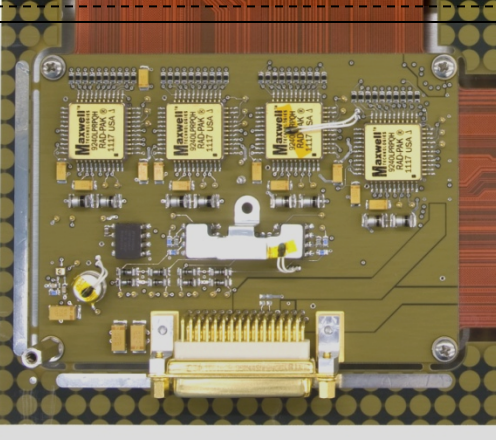
Not at 55K due to dissipation

Digital
Clocking
& Pixel
Addressing



Power
regulators

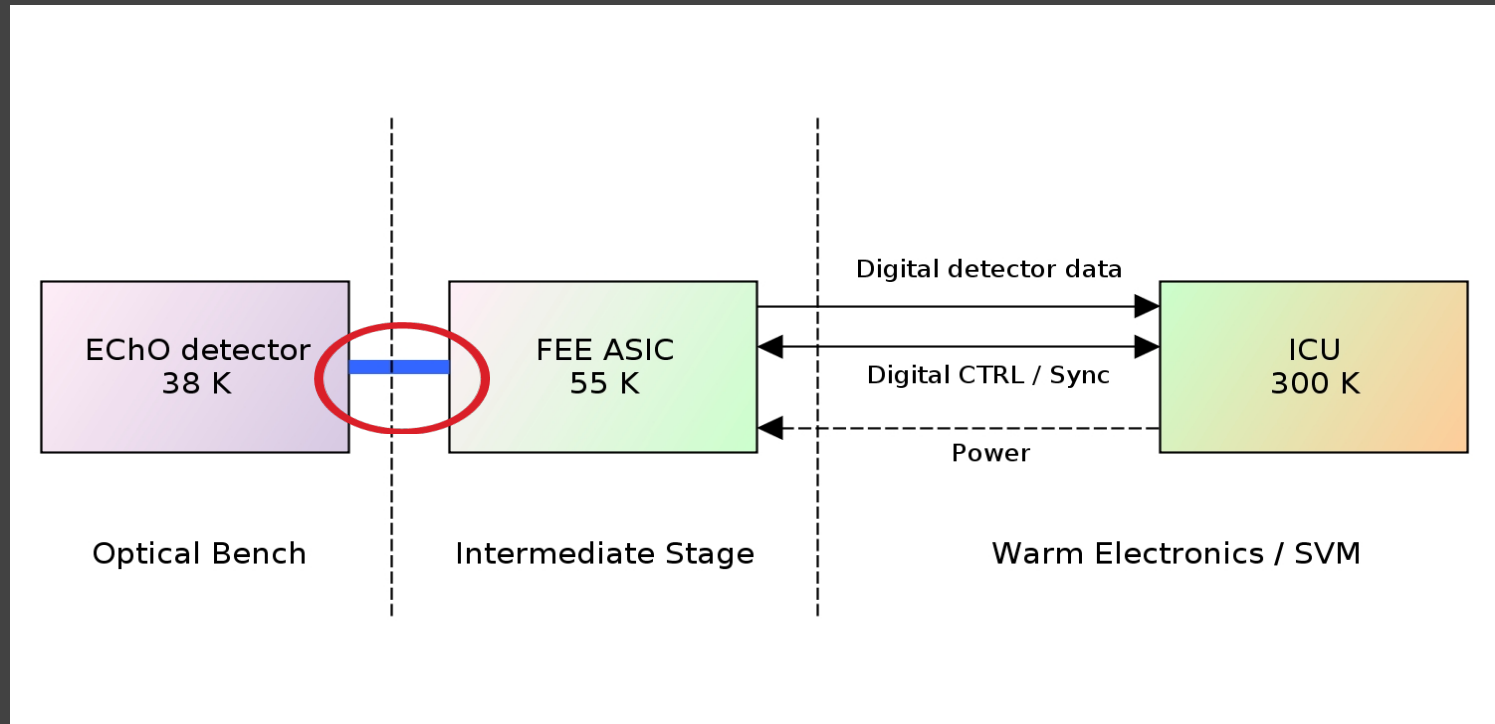
Gain
Offset
subtr.
ADCs



Bias/
ref.
Voltage
regulators

To be integrated in phase 1

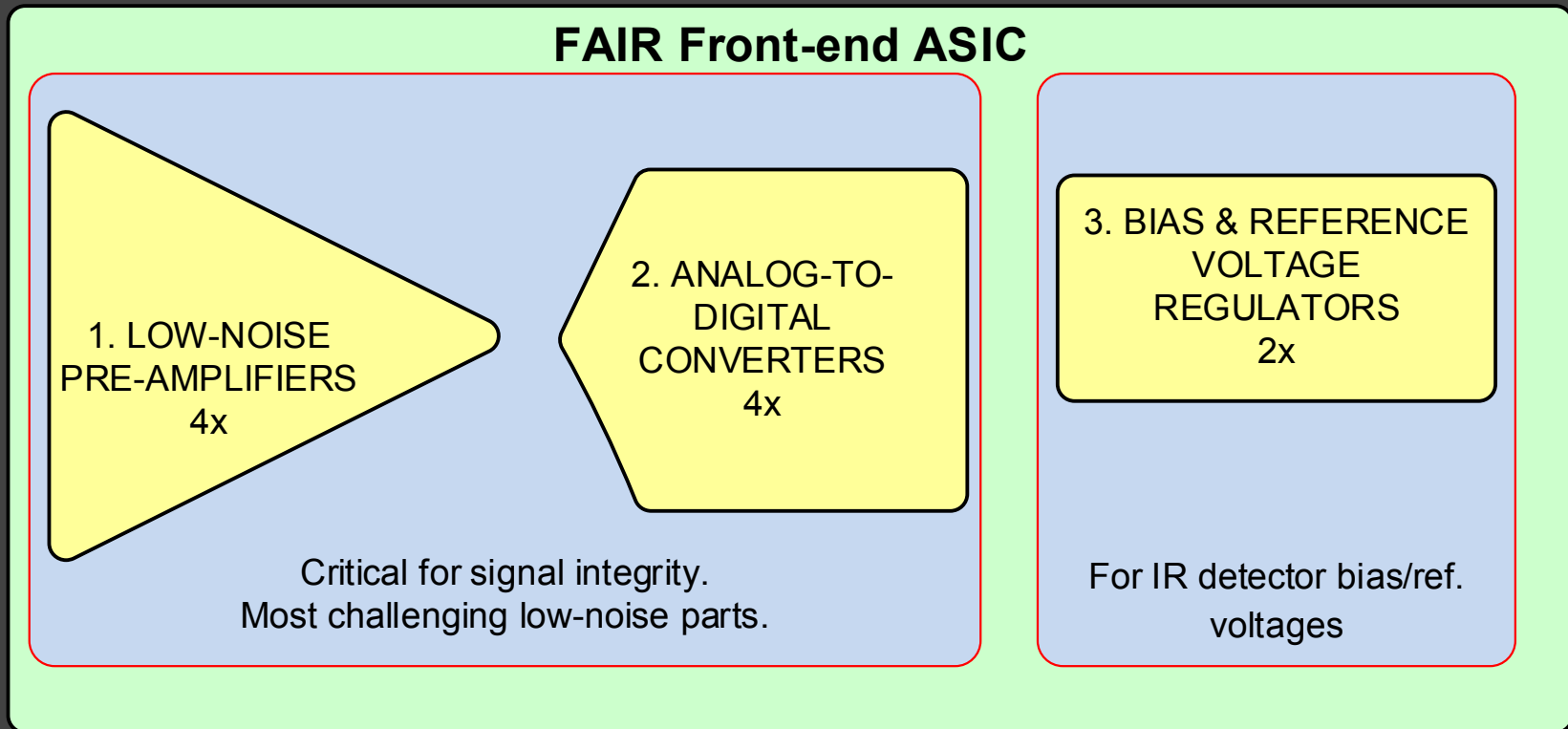
Cryogenic electronic front-end @ 55 Kelvin



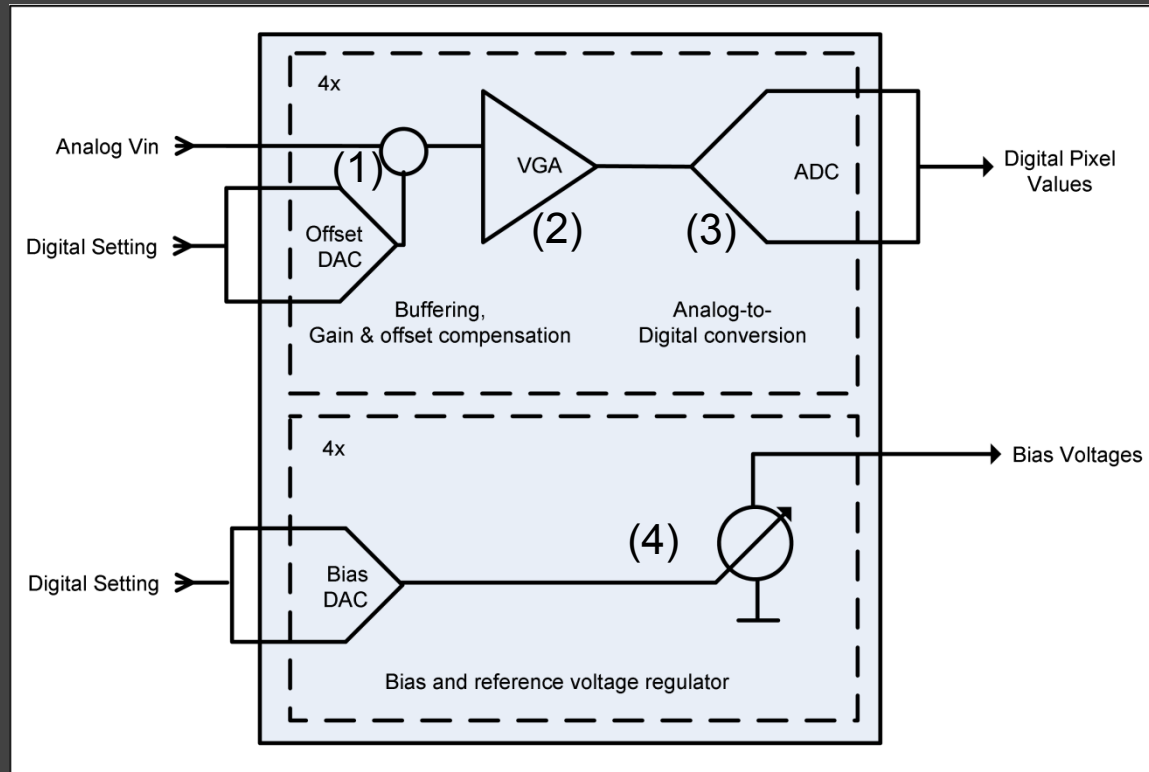
- Close proximity, optimum signal integrity
- Low EMI pickup for sensitive analog signals - **EMI risk mitigation**
- Low-power operation @ 55 Kelvin

Front-end ASIC for InfraRed detector ('FAIR')

- Goal: 'broad compatibility' EU detectors:
1st: **Sofradir (Saturn)** detector chip



All-in-one front-end ASIC



- (1) offset subtraction $\sim 1V$
- (2) variable gain amplifier (VGA) 0dB..18dB (1x..8x)
- (3) 16-bit A-to-D conversion @ 1MS/s
- (4) bias / reference voltage regulators

Front-end key technical specifications

Technology	UMC 0.18um CMOS
Supply voltage	3.3V (analog) 1.8V (digital)
Operating temperature range	40K - 328K

Analog front-end

No. of independent front-end chains	4
Gain settings	1x, 2x, 4x 8x
Offset compensation range	0.5..3V
Offset DAC resolution	24 bits
Analog input voltage range	0V..3V
Analog input capacitance	12-16pF

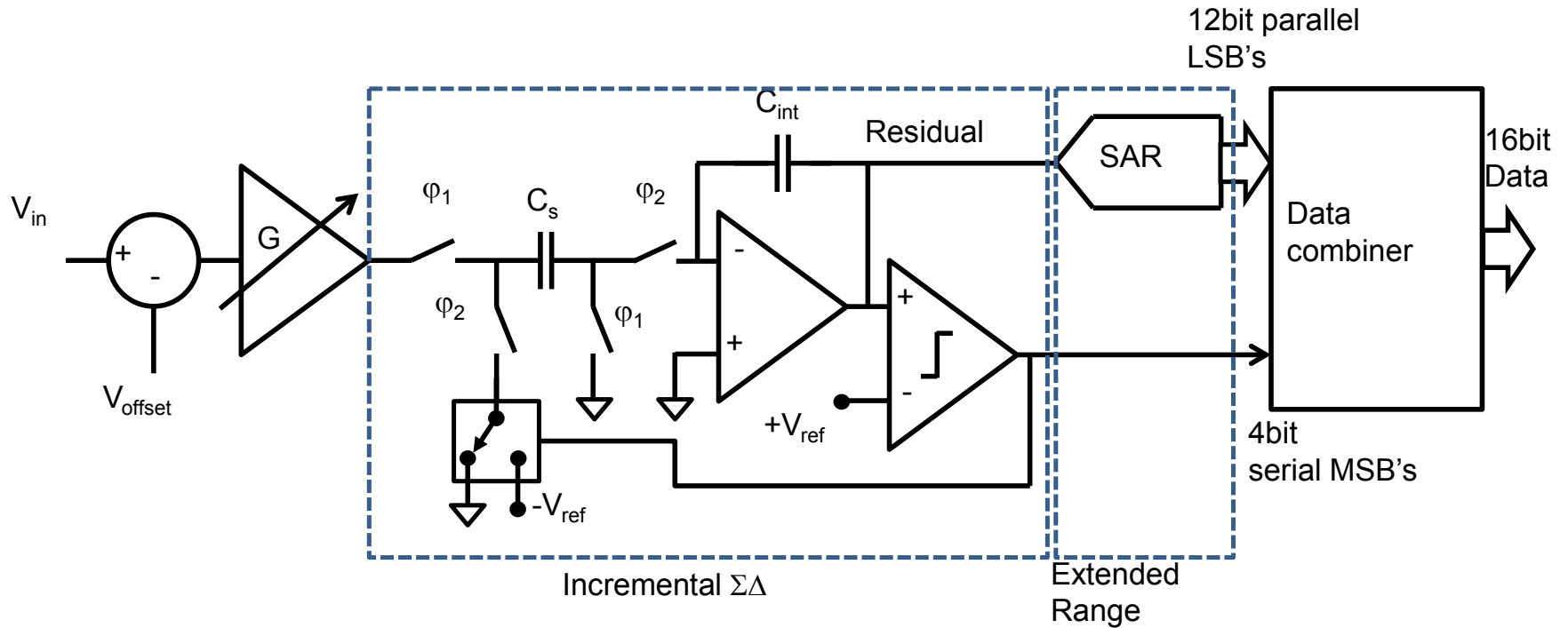
Analog-to-digital converters (ADC)

ADC sampling frequency	1.0 MHz
Analog bandwidth	500kHz
Resolution	16 bits
Effective number of bits (target)	15 ENOBs

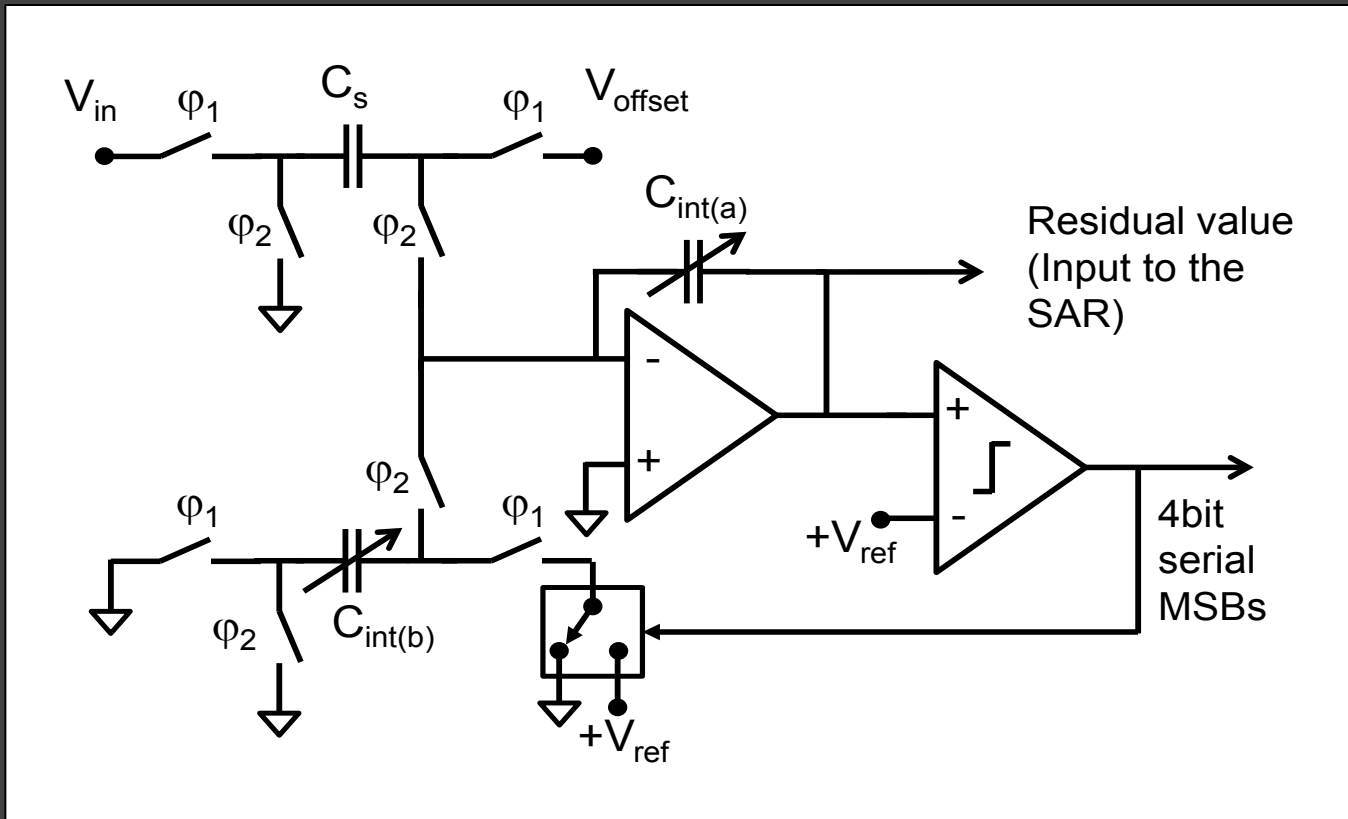
Bias and reference voltage generators

No. of independent regulators	2
Output bias/ref voltage range	0 .. 2.8V
DAC resolution	24 bits
Max current	2mA

Architecture of analog signal processing chain



Incremental sigma-delta front-end circuit with gain and offset cancellation



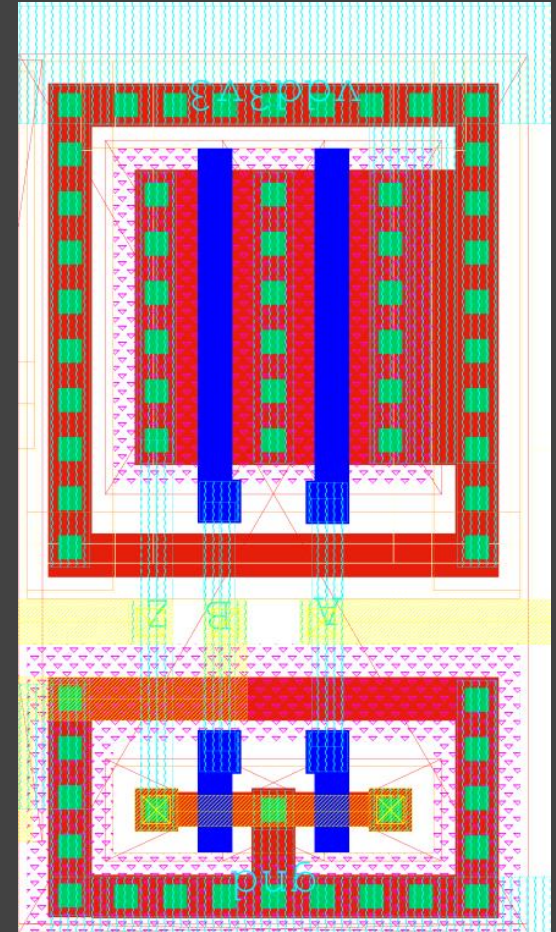
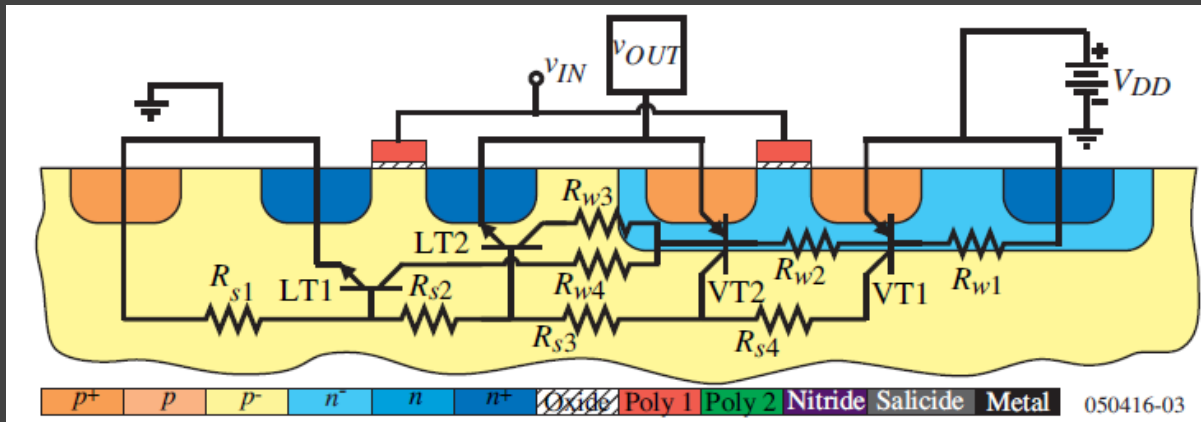
Radiation hardening

Analog

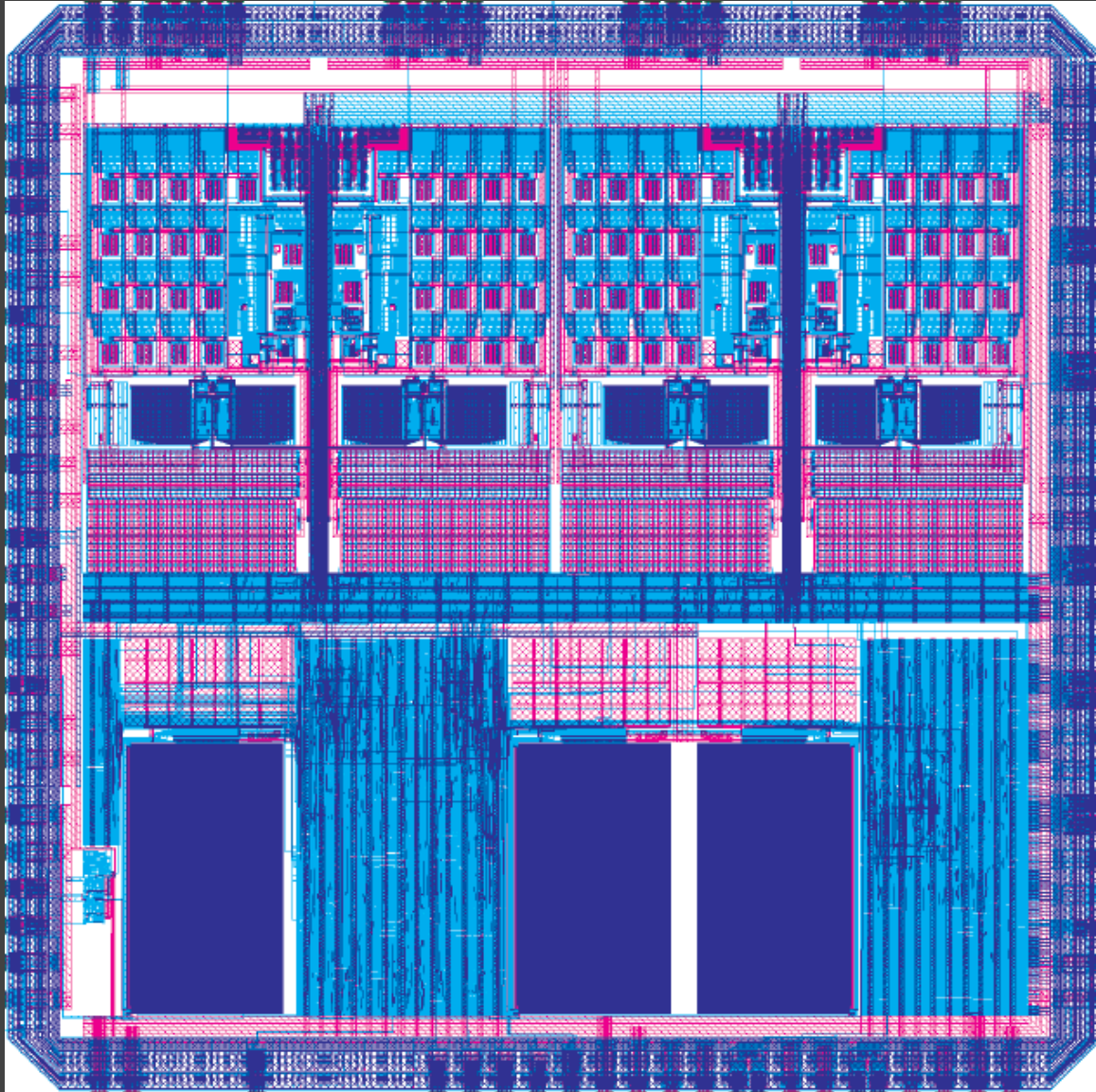
- Guard rings mitigate latchup of parasitic NPN-PNP structure

Digital

- Rad-hard IMEC DARE library



GDS of the complete design



Project timeline

- Project started Q4 2012
- Design phase finished
- Tape-out was March 2014
- Packaged chips expected no 7th July
- Next up: test campaign!
- Mid 2015 >TRL 5

Conclusions

FAIR:

Front-end ASIC for Infrared detector Readout

European read-out ASIC for IR detectors

- 0.18 μm CMOS
- Close proximity, optimum signal integrity
- ADC:
 - 16-bit
 - 1 MSample / s
 - 16mW
 - 2mm²
- Low-power operation @ 55 Kelvin
- Space qualified, rad-hard analog layout



A close-up photograph of a green microchip with numerous gold wire bonds extending from its perimeter. The chip is mounted on a gold-colored substrate. The background is a blurred, golden-yellow surface.

Thank you...



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